

## Tunable $Ta_xN$ Josephson Junctions for Scalable, High Performance, Low Power Computing

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### Abstract

Viable alternatives for high performance, low-power dissipation computing has driven increased interest in superconducting electronics research. Although remarkable progress has been made with Nb/Al-AlO<sub>x</sub>/Nb Josephson junctions, the necessity for low-temperature processing and the electronic defects associated with AlO<sub>x</sub> may ultimately limit the ability to scale this technology to the required density. Alternative barriers such as TaN offer a feasible approach to achieve Josephson junctions with suitable  $I_cR_n$  product and thermal stability for existing microfabrication processes.

We present results obtained for Josephson junctions with varying  $Ta_xN$  composition and thicknesses. A clear dependence of junction behavior on stoichiometry and barrier thickness across a wide range of critical currents and  $I_cR_n$  is observed. Conductivity mapping of AlO<sub>x</sub> and TaN barriers allows a better understanding of the areal distribution of properties across individual junctions.

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